

ELECTRONIC SPECIALTY GASES & SYSTEMS 2023

Day 1: November 14, 2023

Revitalizing Semiconductor Manufacturing in the US	
08:00 AM	Introductory Remarks <i>Michael Corbett, Linx Consulting</i>
08:15 AM	Keynote Speaker: Developments in Specialty Gases <i>Anand Nambiar, EMD Electronic Materials</i>
09:00 AM	Keynote Speaker: The CHIPS Act – What Could Be and Should Be <i>Mark Bohr, Intel Corporation</i>
09:30 AM	A New York Semiconductor State of Mind <i>Leah George Van Scott, Chris Souza, and RJ Ball, NY Economic Development Greater Rochester Enterprise Assets, Genesee County EDC and Empire State Develop</i>
10:00 AM	Networking Break
10:45 AM	Collaborations For Semiconductor Technology <i>Raj Jammy, IMEC</i>
11:15 AM	IRDS Roadmap Update <i>Andreas Neuber, IRDS</i>
11:45 PM	Closing Comments – Break for Lunch
Vapor Phase Materials and Contamination Control	
1:30 PM	Introductory Remarks: Vapor Phase Materials <i>Venkat Pallem, Air Liquide</i>
1:45 PM	Keynote Speaker: Sustainability Studies at IMEC <i>Bram Vangestel, IMEC</i>
2:30 PM	Commercialization of MoO₂Cl₂ for Advanced Node Applications <i>Air Liquide</i>
3:00 PM	Fab In-Line Measurements <i>Nicholai Salovich and Declan Scanlan, Edwards Vacuum</i>
3:30 PM	Networking Break
4:00 PM	Introductory Remarks: Yield and Contamination Control <i>Chris Vroman, Entegris Corporation</i>
4:15 PM	Keynote Speaker: Yield and Contamination Control <i>Jim O'Neil, Entegris Corporation</i>
5:00 PM	Filtration Needs For EUVL <i>ASML</i>
5:30 PM	Contamination Control for ESGs <i>Air Liquide</i>

All The Presentations Will Be Posted at the End of Each Day on Conference Website

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Day 2: November 15, 2023

Analytical Measurements and Metrology	
08:00 AM	Introductory Remarks <i>Hugh Gotts, Air Liquide</i>
08:15 AM	Keynote Speaker: Role of NIST in Supporting the CHIPS Act <i>Marla Dowell, Director, CHIPS R&D Metrology Program</i>
09:00 AM	Special Panel Session: How Do We Close the Analytical Metrology Gap <i>Archita Sengupta – Intel, Raj Jammy – IMEC, Marla Dowell – NIST</i> <i>Hugh Gotts - Moderator</i>
10:00 AM	Networking Break
10:45 AM	Gas Flow Metrology <i>Patrick Lowery, Horiba</i>
11:15 AM	Novel Approach Utilizing APIMS Technology For Analyzing CO and H2 Impurities in Semiconductor UHP Gases <i>Greg Thier, Process Insights</i>
11:45 PM	Closing Comments – Break for Lunch
Facilities, Infrastructure and Components	
1:15 PM	Introductory Remarks <i>Kurtis Fairley, Edwards Vacuum</i>
1:30 PM	Keynote Speaker: Construction Facilities Inputs and Outputs Scrubbers and Reviewing Gas Controls <i>Jake Armstrong, Jacobs Engineering</i>
2:15 PM	Keynote Speaker: Bulk Specialty Gas Delivery Systems <i>TBA, EMD Electronic Materials</i>
2:45 PM	Recycle H2 and Other Gases <i>Zack Dunbar, Edwards Vacuum</i>
3:15 PM	Rare Gas and EUVL Gas Recovery <i>Josh Thornes, ASML</i>
3:45 PM	Networking Break
4:30 PM	SCIS Update <i>Dalia Vernikovsky, ASNA Global</i>
5:00 PM	SCIS <i>Michael Cox, Intel</i>
6:00	Networking reception

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Day 3: November 16, 2023

Market Review	
08:00 AM	Introductory Remarks <i>Mike Corbett, Linx Consulting</i>
08:15 AM	Keynote Speech: Semiconductor Quality Challenges <i>Mike Tseng, TSMC</i>
08:45 AM	Semiconductor Roadmap Update <i>Scotten Jones, Techinsights</i>
9:15 AM	Semiconductor Industry Outlook & Economic Update <i>Duncan Meldrum, Hilltop Economics</i>
9:45 AM	Networking Break
10:15 AM	Helium Market Update <i>Phil Kornbluth, Kornbluth Helium Consulting</i>
10:45 AM	Specialty Gases Market Update <i>Andy Tuan, Linx Consulting</i>
11:15 AM	Closing Keynote Speaker: Sustainability Challenges <i>Ben Gross, Applied Materials</i>
11:45 PM	Conference Closing Comments <i>Mike Corbett, Linx Consulting</i>
12:00	Lunch
Advanced Analytical Measurement & Metrology (AAMM) Workshop	
1:30 PM	Introductory Remarks - IDM and Supplier Challenges and Call for Action <i>Archita Sengupta, Intel</i>
1:45 PM	Introductory Remarks - The Case for Establishing a National Center <i>Hugh Gotts, Air Liquide</i>
2:00 PM	Device Defectivity Challenges <i>Mustafa Badaroglu, Qualcomm</i>
2:25 PM	Advanced Metrology Excellence <i>Marla Dowell NIST</i>
2:50 PM	Need for New SEMI Standards <i>Bob McIntosh, Enviro-E</i>
3:15 PM	Roadmapping & Lab Analysis Perspectives <i>Ashutosh Bhabe, 14-si-solutions</i>
3: 40 PM	Panel Session - Industry Challenges & Developing a National Center for AAMM <i>Archita Sengupta, Hugh Gotts, Mustafa Badaroglu, Marla Dowell</i>
4:30 PM	Conference Closing Comments <i>Mike Corbett, Linx Consulting</i>